



Direct Ink Write Processing Of Signal Crossovers Using Aerosol Jet Printing Method

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Presentation Outline

- Introduction
- Outline
- Crossover Structure Designs
- Results
- Conclusions

Crossovers: Introduction

- Efficient Electronic Integration Requires Signals To Crossover One Another
- RF-DC, RF-RF, DC-DC Signal Crossovers

Current Strategies:

- Multilayered PCBs
 - High Performance (Low Insertion Loss and High Isolation)
 - High Cost
- Surface Mount Technology (SMT) Devices
 - Large Physical Space (5.08 x 5.08 x 1.8 mm³)
 - Rigid Design



Aerosol Jet Printing: Introduction

- Direct Write Technology Create Microscale and Nanoscale 2D or 3D Functional Structures on Flat or Conformal Surfaces
- Materials Include Variety of Aerosolization Capable
 Materials
 - Colloidal Inks
 - Nanoparticle-filled Inks
 - Diluted Thick-film Pastes
 - Thermosetting and UV Curable Polymer Solutions



Aerosol Jet Printing: Process

- Ultrasonic or pneumatic atomization of the ink
- Mist of droplets dense in metal, dielectric, or organic material
- Delivered to the deposition head by a carrier gas (dry nitrogen)
- Focused into a tight stream by coaxial sheath gas
- Deposition onto a substrate 2 to 5 mm below the nozzle



Aerosol Jet Printing: Advantages

- Creation of Features With Dimensions As Small As 5 μm And Up To Several mm
- Wide Range Of Materials
- Ultrasonic Atomization For Ink Viscosities Up to 7 cP
- Pneumatic Atomization For Ink Viscosities Up To 1000 cP



Pros and Cons



Pros:

• Flip Chip Soldering

Cons:

- Limited Frequency Range
- Limited Power Handling
- Design Revolves Around The Chip



Direct Write Technology

Pros:

- Printing at specific locations
- Features as small as 5 μm
- Wide range of materials
- Design Freedom

Cons:

Ink availability

Outline



Outline

Objective:

Reliably Print Crossover Structures Structures Under Study:

- Dielectric Pad Design
- Dielectric Ramp Design

Materials Under Study:

- Benzocyclobutene (BCB, dielectric $[\epsilon_r=2.65 (1 \text{ GHz})]$, thermally curable)
- Norland Electronic Adhesive 121(NEA, dielectric [ε_r=4.04 (1 MHz)], UV curable)
- Electroninks 615 (EI-615, conductor, thermally curable)

Equipment

- Optomec's AJ 200
- Agilent 8720ES S-parameter
 Network Analyzer
- BK Precision 1743b DC Power
 Supply
- FLIR ETS320 Thermal Camera
- Keyence, DekTak, and Multimeter



Outline

- 2 Crossover Structures Were Designed (Pad And Ramp)
- 5 NEA and 5 BCB Crossover Structures Were Printed
- EI-615 Was Printed Over The Crossover And Connected The DC Circuit Traces
- Samples Were Connected To A Network Analyzer And DC Power Supply
- DC Carrying Capability And Changes In The S21 Parameter Were Recorded
- Recorded Heat Spread Via A Thermal Camera



Prefabricated boards were used as the substrate for testing the crossovers

Ink Settings

Ink	Nozzle Size (µm)	Sheath Gas Flow (ccm)	Ultrasonic Atomizer Gas Flow (ccm)	Ultrasonic Atomizer Power (mA)	Pneumatic Atomizer Gas Flow (ccm)	Pneumatic Exhaust Gas Flow (ccm)	Curing Type
BCB	300	30	35	0.5	Х	Х	Thermal
NEA 121	300	40	X	X	910	850	UV
EI-615	150 or 200	50	7	0.3	X	X	Thermal

Creation Of Tool Paths



mport Generic Fill Image	s Export Tool Config Ref I *		
Serpentine Fill	General Settings		
Angle 90 🔶 Deg	Trace Width 0.037 🖈 Units		
Max Join Dist. (Trace Width Multiple)	Min Overlap 0 - Max Overlap		
Enforce bounds	Join All Segments		
Island Detect	V Offset Outline		
	Remove Outline		
Sementine	Auto Radius Fill		
Serpenane	Fill to Different Layer		
Perimeter Fil	Circle Fill		
Continous	5 🚔 Degrees / Arc		
Perimeter	Circle		
Miscellaneous Tools	Auto Radius Al Polylines Radius 0.050 💠		
Sort	Apply		
Join Undo	3		



Pad Design



Ramp Design



Conductive Trace Designs



Printing Of Crossover Structures





Completed Crossovers



Completed Crossovers



Results: BCB Trench Filling



Results: NEA Trench Filling



Results: Pads Vs Ramps



Results: Pads Vs Ramps



NEA Pad Tilting

Conformal Printing Print Direction Discolored Area Is A Repaired Print Time 2.25.4

Results: NEA Pad I-V Curves

NEA Pad Structures

- Average Survival Current Up To 0.5 A
- Max Survival Current Up To
 1.39 A



Results: BCB Ramp I-V Curves

BCB Ramp Structures

- Average Survival Current Up To 1.3 A
- Max Survival Current Up To
 2.772 A



BCB Ramp Crossover Structures

Results: NEA Pad Power Handling

NEA Pad Structures

- Average Survival Power Up To 0.36 W
- Max Survival Power Up To
 2.224 W
- Largest ΔS21: 0.271 dB



Results: BCB Ramp Power Handling

BCB Ramp Crossover Structures



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Failure Analysis: BCB Ramp

2nd Test

1st Test: Before/After











Failure Analysis



Thermal Analysis: BCB Ramp



Thermal Analysis: NEA Pad



Comparison To COTS SMT Devices

COTS SMT Devices:

- MLO[®] SMT RF-DC Crossover Footprint: 4.98 x 4.98 x 0.46 mm³
 - Specifications: 9 W at 6 GHz
- X2BS Crossover Footprint: 5.08 x 5.08 x 1.8 mm³
 - Specifications: 10 W at 6 GHz

Printed Crossovers:

- Pad Design: 3.8 x 2.3 x 0.365 mm³, 2.224 W at 10 GHz
 - 3.6x vol. reduction and 2.8x area reduction to MLO[®]
 - 15.7x vol. reduction and 3.0x area reduction to X2BS
- Ramp Design: 3.65 x 1.15 x 0.141 mm³, 6.93 W at 10 GHz
 - 19.3x vol. reduction and 5.9x area reduction to MLO[®]
 - 78.7x vol reduction and 6.1x area reduction to X2BS



Conclusions

5 NEA Pad and 5 BCB Ramp Crossover Structures Were Printed

	Maximum Power (W)	Maximum ∆S21 at 10 GHz (dB)	Maximum Temperature (°C)
NEA Pads	2.224	0.271	273.0
BCB Ramps	6.93	0.339	248.6

- Comparable to COTS SMT Components:
 - Slightly Less Power Handling
 - 6.1x reduction in physical board space
 - Extremely Tailorable: Materials, Shape, Specifications

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